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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

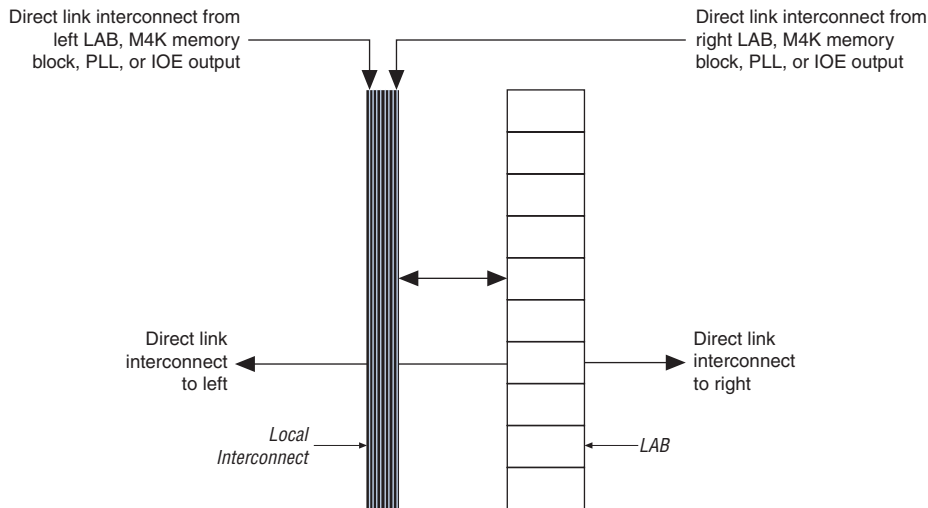
The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	598
Number of Logic Elements/Cells	5980
Total RAM Bits	92160
Number of I/O	185
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-BGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/ep1c6f256c6n">https://www.e-xfl.com/product-detail/intel/ep1c6f256c6n</a>

performance and flexibility. Each LE can drive 30 other LEs through fast local and direct link interconnects. Figure 2–3 shows the direct link connection.

**Figure 2–3. Direct Link Connection**



## LAB Control Signals

Each LAB contains dedicated logic for driving control signals to its LEs. The control signals include two clocks, two clock enables, two asynchronous clears, synchronous clear, asynchronous preset/load, synchronous load, and add/subtract control signals. This gives a maximum of 10 control signals at a time. Although synchronous load and clear signals are generally used when implementing counters, they can also be used with other functions.

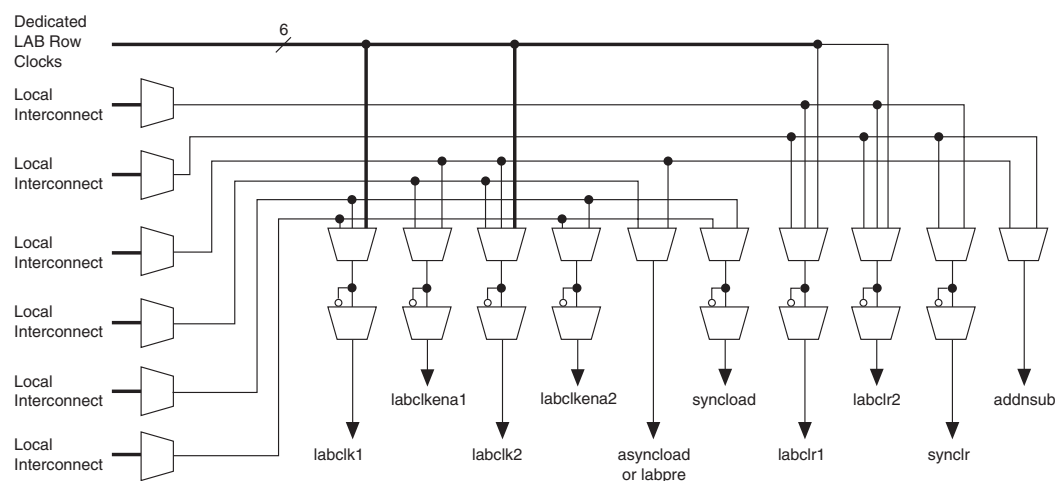
Each LAB can use two clocks and two clock enable signals. Each LAB's clock and clock enable signals are linked. For example, any LE in a particular LAB using the `labclk1` signal will also use `labckena1`. If the LAB uses both the rising and falling edges of a clock, it also uses both LAB-wide clock signals. Deasserting the clock enable signal will turn off the LAB-wide clock.

Each LAB can use two asynchronous clear signals and an asynchronous load/preset signal. The asynchronous load acts as a preset when the asynchronous load data input is tied high.

With the LAB-wide `addnsub` control signal, a single LE can implement a one-bit adder and subtractor. This saves LE resources and improves performance for logic functions such as DSP correlators and signed multipliers that alternate between addition and subtraction depending on data.

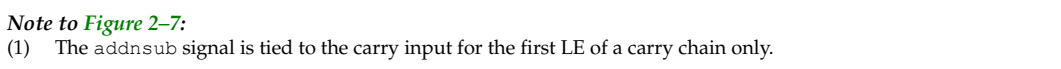
The LAB row clocks [5 : 0] and LAB local interconnect generate the LAB-wide control signals. The MultiTrack™ interconnect's inherent low skew allows clock and control signal distribution in addition to data. [Figure 2-4](#) shows the LAB control signal generation circuit.

**Figure 2-4. LAB-Wide Control Signals**



## Logic Elements

The smallest unit of logic in the Cyclone architecture, the LE, is compact and provides advanced features with efficient logic utilization. Each LE contains a four-input LUT, which is a function generator that can implement any function of four variables. In addition, each LE contains a programmable register and carry chain with carry select capability. A single LE also supports dynamic single bit addition or subtraction mode selectable by a LAB-wide control signal. Each LE drives all types of interconnects: local, row, column, LUT chain, register chain, and direct link interconnects. See [Figure 2-5](#).



The carry-select chain provides a very fast carry-select function between LEs in dynamic arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 0 and carry-in of 1 in parallel. The `carry-in0` and `carry-in1` signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within a LAB.

**Altera Corporation**  
**May 2008**

The Quartus II Compiler automatically creates carry chain logic during design processing, or you can create it manually during design entry. Parameterized functions such as LPM functions automatically take advantage of carry chains for the appropriate functions.

The Quartus II Compiler creates carry chains longer than 10 LEs by linking LABs together automatically. For enhanced fitting, a long carry chain runs vertically allowing fast horizontal connections to M4K memory blocks. A carry chain can continue as far as a full column.

### *Clear and Preset Logic Control*

LAB-wide signals control the logic for the register's clear and preset signals. The LE directly supports an asynchronous clear and preset function. The register preset is achieved through the asynchronous load of a logic high. The direct asynchronous preset does not require a NOT-gate push-back technique. Cyclone devices support simultaneous preset/ asynchronous load and clear signals. An asynchronous clear signal takes precedence if both signals are asserted simultaneously. Each LAB supports up to two clears and one preset signal.

In addition to the clear and preset ports, Cyclone devices provide a chip-wide reset pin (DEV\_CLRn) that resets all registers in the device. An option set before compilation in the Quartus II software controls this pin. This chip-wide reset overrides all other control signals.

## **MultiTrack Interconnect**

In the Cyclone architecture, connections between LEs, M4K memory blocks, and device I/O pins are provided by the MultiTrack interconnect structure with DirectDrive™ technology. The MultiTrack interconnect consists of continuous, performance-optimized routing lines of different speeds used for inter- and intra-design block connectivity. The Quartus II Compiler automatically places critical design paths on faster interconnects to improve design performance.

DirectDrive technology is a deterministic routing technology that ensures identical routing resource usage for any function regardless of placement within the device. The MultiTrack interconnect and DirectDrive technology simplify the integration stage of block-based designing by eliminating the re-optimization cycles that typically follow design changes and additions.

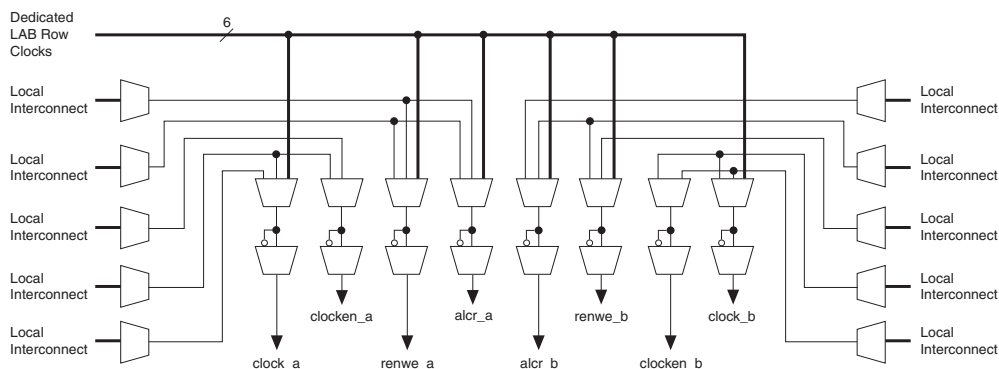
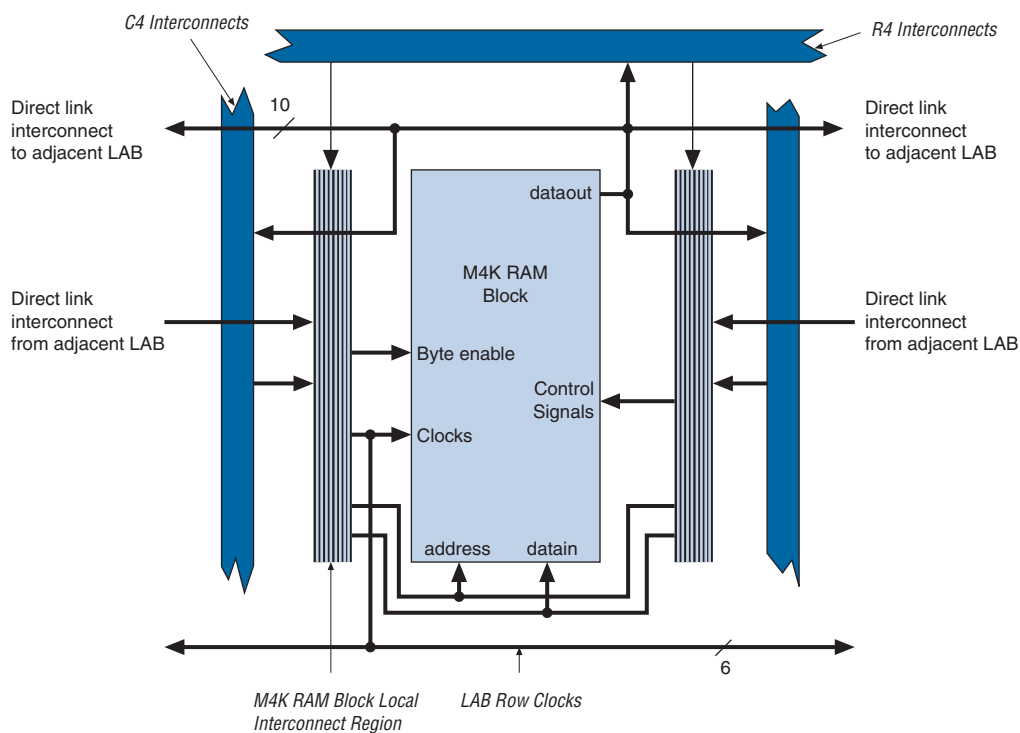
The MultiTrack interconnect consists of row and column interconnects that span fixed distances. A routing structure with fixed length resources for all devices allows predictable and repeatable performance when

migrating through different device densities. Dedicated row interconnects route signals to and from LABs, PLLs, and M4K memory blocks within the same row. These row resources include:

- Direct link interconnects between LABs and adjacent blocks
- R4 interconnects traversing four blocks to the right or left

The direct link interconnect allows a LAB or M4K memory block to drive into the local interconnect of its left and right neighbors. Only one side of a PLL block interfaces with direct link and row interconnects. The direct link interconnect provides fast communication between adjacent LABs and/or blocks without using row interconnect resources.

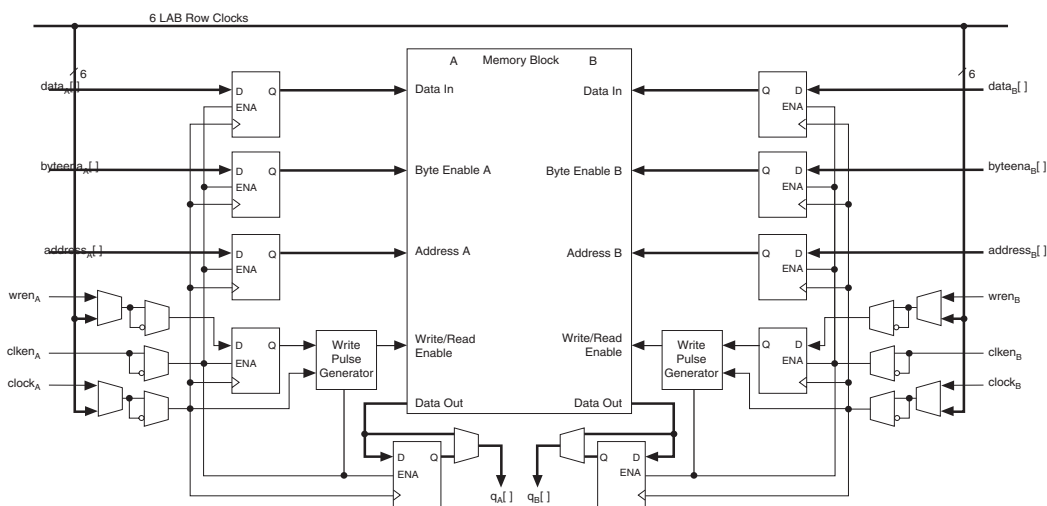
The R4 interconnects span four LABs, or two LABs and one M4K RAM block. These resources are used for fast row connections in a four-LAB region. Every LAB has its own set of R4 interconnects to drive either left or right. [Figure 2–9](#) shows R4 interconnect connections from a LAB. R4 interconnects can drive and be driven by M4K memory blocks, PLLs, and row IOEs. For LAB interfacing, a primary LAB or LAB neighbor can drive a given R4 interconnect. For R4 interconnects that drive to the right, the primary LAB and right neighbor can drive on to the interconnect. For R4 interconnects that drive to the left, the primary LAB and its left neighbor can drive on to the interconnect. R4 interconnects can drive other R4 interconnects to extend the range of LABs they can drive. R4 interconnects can also drive C4 interconnects for connections from one row to another.

**Figure 2–15. M4K RAM Block Control Signals****Figure 2–16. M4K RAM Block LAB Row Interface**

## Independent Clock Mode

The M4K memory blocks implement independent clock mode for true dual-port memory. In this mode, a separate clock is available for each port (ports A and B). Clock A controls all registers on the port A side, while clock B controls all registers on the port B side. Each port, A and B, also supports independent clock enables and asynchronous clear signals for port A and B registers. Figure 2–17 shows an M4K memory block in independent clock mode.

**Figure 2–17. Independent Clock Mode** Notes (1), (2)



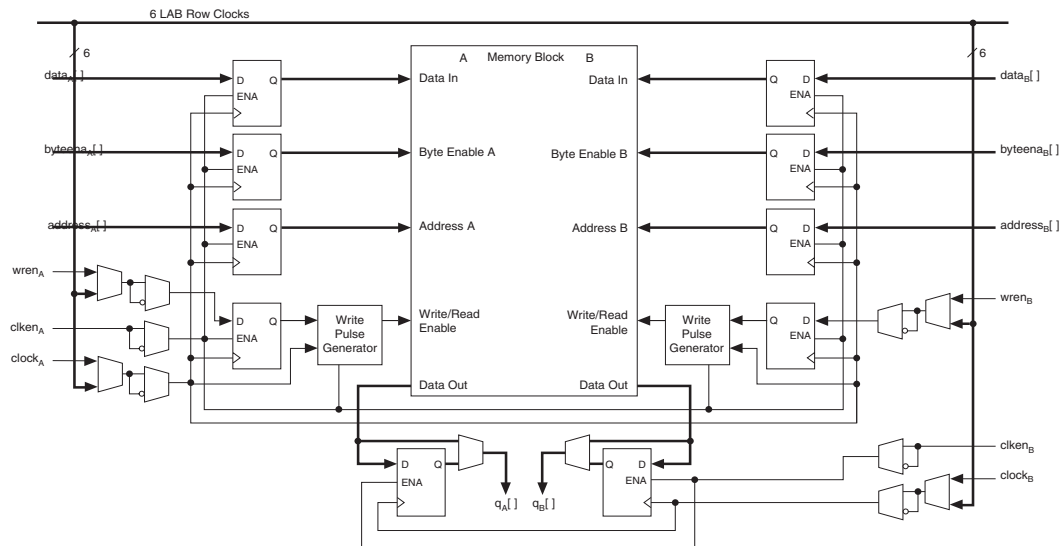
Notes to Figure 2–17:

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

## Input/Output Clock Mode

Input/output clock mode can be implemented for both the true and simple dual-port memory modes. On each of the two ports, A or B, one clock controls all registers for inputs into the memory block: data input, wren, and address. The other clock controls the block's data output registers. Each memory block port, A or B, also supports independent clock enables and asynchronous clear signals for input and output registers. Figures 2–18 and 2–19 show the memory block in input/output clock mode.



**Figure 2–18. Input/Output Clock Mode in True Dual-Port Mode** *Notes (1), (2)***Notes to Figure 2–18:**

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

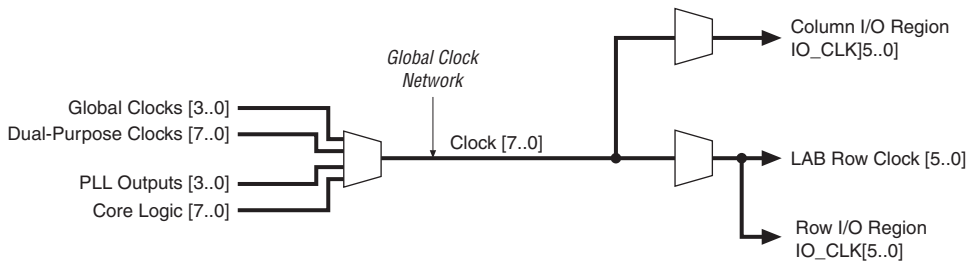
## Dual-Purpose Clock Pins

Each Cyclone device except the EP1C3 device has eight dual-purpose clock pins,  $DPCLK[7..0]$  (two on each I/O bank). EP1C3 devices have five  $DPCLK$  pins in the 100-pin TQFP package. These dual-purpose pins can connect to the global clock network (see [Figure 2–22](#)) for high-fanout control signals such as clocks, asynchronous clears, presets, and clock enables, or protocol control signals such as  $TRDY$  and  $IRDY$  for PCI, or  $DQS$  signals for external memory interfaces.

## Combined Resources

Each Cyclone device contains eight distinct dedicated clocking resources. The device uses multiplexers with these clocks to form six-bit buses to drive LAB row clocks, column IOE clocks, or row IOE clocks. See [Figure 2–23](#). Another multiplexer at the LAB level selects two of the six LAB row clocks to feed the LE registers within the LAB.

**Figure 2–23. Global Clock Network Multiplexers**



IOE clocks have row and column block regions. Six of the eight global clock resources feed to these row and column regions. [Figure 2–24](#) shows the I/O clock regions.

## External Clock Inputs

Each PLL supports single-ended or differential inputs for source-synchronous receivers or for general-purpose use. The dedicated clock pins (CLK[3..0]) feed the PLL inputs. These dual-purpose pins can also act as LVDS input pins. See [Figure 2-25](#).

[Table 2-8](#) shows the I/O standards supported by PLL input and output pins.

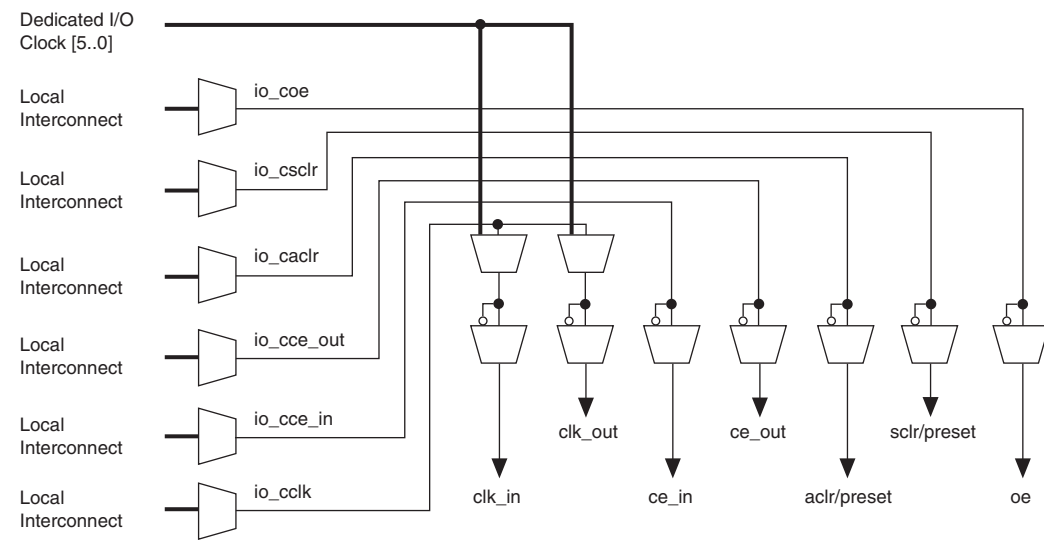
<b>Table 2-8. PLL I/O Standards</b>		
<b>I/O Standard</b>	<b>CLK Input</b>	<b>EXTCLK Output</b>
3.3-V LVTTL/LVCMOS	✓	✓
2.5-V LVTTL/LVCMOS	✓	✓
1.8-V LVTTL/LVCMOS	✓	✓
1.5-V LVCMOS	✓	✓
3.3-V PCI	✓	✓
LVDS	✓	✓
SSTL-2 class I	✓	✓
SSTL-2 class II	✓	✓
SSTL-3 class I	✓	✓
SSTL-3 class II	✓	✓
Differential SSTL-2	—	✓

For more information on LVDS I/O support, refer to “[LVDS I/O Pins](#)” on [page 2-54](#).

## External Clock Outputs

Each PLL supports one differential or one single-ended output for source-synchronous transmitters or for general-purpose external clocks. If the PLL does not use these PLL\_OUT pins, the pins are available for use as general-purpose I/O pins. The PLL\_OUT pins support all I/O standards shown in [Table 2-8](#).

The external clock outputs do not have their own V<sub>CC</sub> and ground voltage supplies. Therefore, to minimize jitter, do not place switching I/O pins next to these output pins. The EP1C3 device in the 100-pin TQFP package

**Figure 2–31. Control Signal Selection per IOE**

In normal bidirectional operation, you can use the input register for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register is available for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from the local interconnect in the associated LAB, dedicated I/O clocks, or the column and row interconnects.

Figure 2–32 shows the IOE in bidirectional configuration.

<b>Table 2–10. DQ Pin Groups (Part 2 of 2)</b>			
<b>Device</b>	<b>Package</b>	<b>Number of × 8 DQ Pin Groups</b>	<b>Total DQ Pin Count</b>
EP1C6	144-pin TQFP	4	32
	240-pin PQFP	4	32
	256-pin FineLine BGA	4	32
EP1C12	240-pin PQFP	4	32
	256-pin FineLine BGA	4	32
	324-pin FineLine BGA	8	64
EP1C20	324-pin FineLine BGA	8	64
	400-pin FineLine BGA	8	64

**Note to Table 2–10:**

- (1) EP1C3 devices in the 100-pin TQFP package do not have any DQ pin groups in I/O bank 1.

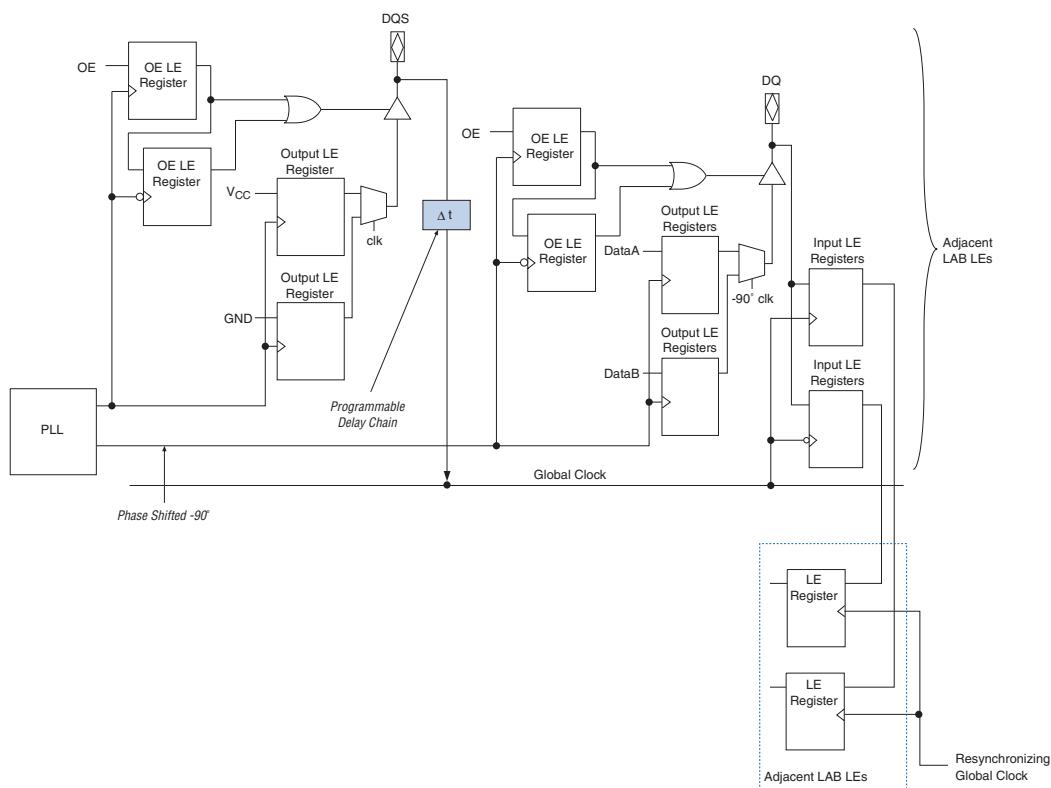
A programmable delay chain on each DQS pin allows for either a 90° phase shift (for DDR SDRAM), or a 72° phase shift (for FCRAM) which automatically center-aligns input DQS synchronization signals within the data window of their corresponding DQ data signals. The phase-shifted DQS signals drive the global clock network. This global DQS signal clocks DQ signals on internal LE registers.

These DQS delay elements combine with the PLL's clocking and phase shift ability to provide a complete hardware solution for interfacing to high-speed memory.

The clock phase shift allows the PLL to clock the DQ output enable and output paths. The designer should use the following guidelines to meet 133 MHz performance for DDR SDRAM and FCRAM interfaces:

- The DQS signal must be in the middle of the DQ group it clocks
- Resynchronize the incoming data to the logic array clock using successive LE registers or FIFO buffers
- LE registers must be placed in the LAB adjacent to the DQ I/O pin column it is fed by

Figure 2–34 illustrates DDR SDRAM and FCRAM interfacing from the I/O through the dedicated circuitry to the logic array.

**Figure 2–34. DDR SDRAM and FCRAM Interfacing**

## Programmable Drive Strength

The output buffer for each Cyclone device I/O pin has a programmable drive strength control for certain I/O standards. The LVTTTL and LVCMOS standards have several levels of drive strength that the designer can control. SSTL-3 class I and II, and SSTL-2 class I and II support a minimum setting, the lowest drive strength that guarantees the  $I_{OH}/I_{OL}$

## Advanced I/O Standard Support

Cyclone device IOEs support the following I/O standards:

- 3.3-V LVTTL/LVCMOS
- 2.5-V LVTTL/LVCMOS
- 1.8-V LVTTL/LVCMOS
- 1.5-V LVCMOS
- 3.3-V PCI
- LVDS
- RSDS
- SSTL-2 class I and II
- SSTL-3 class I and II
- Differential SSTL-2 class II (on output clocks only)

Table 2–12 describes the I/O standards supported by Cyclone devices.

<b>I/O Standard</b>	<b>Type</b>	<b>Input Reference Voltage (<math>V_{REF}</math>) (V)</b>	<b>Output Supply Voltage (<math>V_{CCIO}</math>) (V)</b>	<b>Board Termination Voltage (<math>V_{TT}</math>) (V)</b>
3.3-V LVTTL/LVCMOS	Single-ended	N/A	3.3	N/A
2.5-V LVTTL/LVCMOS	Single-ended	N/A	2.5	N/A
1.8-V LVTTL/LVCMOS	Single-ended	N/A	1.8	N/A
1.5-V LVCMOS	Single-ended	N/A	1.5	N/A
3.3-V PCI (1)	Single-ended	N/A	3.3	N/A
LVDS (2)	Differential	N/A	2.5	N/A
RSDS (2)	Differential	N/A	2.5	N/A
SSTL-2 class I and II	Voltage-referenced	1.25	2.5	1.25
SSTL-3 class I and II	Voltage-referenced	1.5	3.3	1.5
Differential SSTL-2 (3)	Differential	1.25	2.5	1.25

**Notes to Table 2–12:**

- (1) There is no megafunction support for EP1C3 devices for the PCI compiler. However, EP1C3 devices support PCI by using the LVTTL 16-mA I/O standard and drive strength assignments in the Quartus II software. The device requires an external diode for PCI compliance.
- (2) EP1C3 devices in the 100-pin TQFP package do not support the LVDS and RSDS I/O standards.
- (3) This I/O standard is only available on output clock pins ( $PLL\_OUT$  pins). EP1C3 devices in the 100-pin package do not support this I/O standard as it does not have  $PLL\_OUT$  pins.

Cyclone devices contain four I/O banks, as shown in Figure 2–35. I/O banks 1 and 3 support all the I/O standards listed in Table 2–12. I/O banks 2 and 4 support all the I/O standards listed in Table 2–12 except the 3.3-V PCI standard. I/O banks 2 and 4 contain dual-purpose DQS, DQ,

**Table 4–5. LVCMOS Specifications**

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCIO}$	Output supply voltage	—	3.0	3.6	V
$V_{IH}$	High-level input voltage	—	1.7	4.1	V
$V_{IL}$	Low-level input voltage	—	–0.5	0.7	V
$V_{OH}$	High-level output voltage	$V_{CCIO} = 3.0$ , $I_{OH} = -0.1$ mA	$V_{CCIO} - 0.2$	—	V
$V_{OL}$	Low-level output voltage	$V_{CCIO} = 3.0$ , $I_{OL} = 0.1$ mA	—	0.2	V

**Table 4–6. 2.5-V I/O Specifications**

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCIO}$	Output supply voltage	—	2.375	2.625	V
$V_{IH}$	High-level input voltage	—	1.7	4.1	V
$V_{IL}$	Low-level input voltage	—	–0.5	0.7	V
$V_{OH}$	High-level output voltage	$I_{OH} = -0.1$ mA	2.1	—	V
		$I_{OH} = -1$ mA	2.0	—	V
		$I_{OH} = -2$ to $-16$ mA (11)	1.7	—	V
$V_{OL}$	Low-level output voltage	$I_{OL} = 0.1$ mA	—	0.2	V
		$I_{OH} = 1$ mA	—	0.4	V
		$I_{OH} = 2$ to $16$ mA (11)	—	0.7	V

**Table 4–7. 1.8-V I/O Specifications**

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
$V_{CCIO}$	Output supply voltage	—	1.65	1.95	V
$V_{IH}$	High-level input voltage	—	$0.65 \times V_{CCIO}$	2.25 (12)	V
$V_{IL}$	Low-level input voltage	—	–0.3	$0.35 \times V_{CCIO}$	V
$V_{OH}$	High-level output voltage	$I_{OH} = -2$ to $-8$ mA (11)	$V_{CCIO} - 0.45$	—	V
$V_{OL}$	Low-level output voltage	$I_{OL} = 2$ to $8$ mA (11)	—	0.45	V



**Table 4–22. IOE Internal Timing Microparameter Descriptions**

Symbol	Parameter
$t_{SU}$	IOE input and output register setup time before clock
$t_H$	IOE input and output register hold time after clock
$t_{CO}$	IOE input and output register clock-to-output delay
$t_{PIN2COMBOUT\_R}$	Row input pin to IOE combinatorial output
$t_{PIN2COMBOUT\_C}$	Column input pin to IOE combinatorial output
$t_{COMBIN2PIN\_R}$	Row IOE data input to combinatorial output pin
$t_{COMBIN2PIN\_C}$	Column IOE data input to combinatorial output pin
$t_{CLR}$	Minimum clear pulse width
$t_{PRE}$	Minimum preset pulse width
$t_{CLKHL}$	Minimum clock high or low time

**Table 4–23. M4K Block Internal Timing Microparameter Descriptions**

Symbol	Parameter
$t_{M4KRC}$	Synchronous read cycle time
$t_{M4KWC}$	Synchronous write cycle time
$t_{M4KWERESU}$	Write or read enable setup time before clock
$t_{M4KWEREH}$	Write or read enable hold time after clock
$t_{M4KBESU}$	Byte enable setup time before clock
$t_{M4KBEH}$	Byte enable hold time after clock
$t_{M4KDATAASU}$	A port data setup time before clock
$t_{M4KDATAAH}$	A port data hold time after clock
$t_{M4KADDRASU}$	A port address setup time before clock
$t_{M4KADDRAH}$	A port address hold time after clock
$t_{M4KDATABSU}$	B port data setup time before clock
$t_{M4KDATABH}$	B port data hold time after clock
$t_{M4KADDRBSU}$	B port address setup time before clock
$t_{M4KADDRBH}$	B port address hold time after clock
$t_{M4KDATAO1}$	Clock-to-output delay when using output registers
$t_{M4KDATAO2}$	Clock-to-output delay without output registers
$t_{M4KCLKHL}$	Minimum clock high or low time
$t_{M4KCLR}$	Minimum clear pulse width

Tables 4–34 through 4–35 show the external timing parameters on column and row pins for EP1C6 devices.

**Table 4–34. EP1C6 Column Pin Global Clock External I/O Timing Parameters**

Symbol	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	2.691	—	3.094	—	3.496	—	ns
$t_{\text{INH}}$	0.000	—	0.000	—	0.000	—	ns
$t_{\text{OUTCO}}$	2.000	3.917	2.000	4.503	2.000	5.093	ns
$t_{\text{INSUPLL}}$	1.513	—	1.739	—	1.964	—	ns
$t_{\text{INHPLL}}$	0.000	—	0.000	—	0.000	—	ns
$t_{\text{OUTCOPLL}}$	0.500	2.038	0.500	2.343	0.500	2.651	ns

**Table 4–35. EP1C6 Row Pin Global Clock External I/O Timing Parameters**

Symbol	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	2.774	—	3.190	—	3.605	—	ns
$t_{\text{INH}}$	0.000	—	0.000	—	0.000	—	ns
$t_{\text{OUTCO}}$	2.000	3.817	2.000	4.388	2.000	4.963	ns
$t_{\text{INSUPLL}}$	1.596	—	1.835	—	2.073	—	ns
$t_{\text{INHPLL}}$	0.000	—	0.000	—	0.000	—	ns
$t_{\text{OUTCOPLL}}$	0.500	1.938	0.500	2.228	0.500	2.521	ns

Tables 4–36 through 4–37 show the external timing parameters on column and row pins for EP1C12 devices.

**Table 4–36. EP1C12 Column Pin Global Clock External I/O Timing Parameters (Part 1 of 2)**

Symbol	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$	2.510	—	2.885	—	3.259	—	ns
$t_{\text{INH}}$	0.000	—	0.000	—	0.000	—	ns
$t_{\text{OUTCO}}$	2.000	3.798	2.000	4.367	2.000	4.940	ns
$t_{\text{INSUPLL}}$	1.588	—	1.824	—	2.061	—	ns

**Table 4–42. Cyclone I/O Standard Output Delay Adders for Fast Slew Rate on Column Pins (Part 2 of 2)**

Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
2.5-V LVTTTL	2 mA	—	329	—	378	—	427	ps
	8 mA	—	–661	—	–761	—	–860	ps
	12 mA	—	–655	—	–754	—	–852	ps
	16 mA	—	–795	—	–915	—	–1034	ps
1.8-V LVTTTL	2 mA	—	4	—	4	—	5	ps
	8 mA	—	–208	—	–240	—	–271	ps
	12 mA	—	–208	—	–240	—	–271	ps
1.5-V LVTTTL	2 mA	—	2,288	—	2,631	—	2,974	ps
	4 mA	—	608	—	699	—	790	ps
	8 mA	—	292	—	335	—	379	ps
SSTL-3 class I		—	–410	—	–472	—	–533	ps
SSTL-3 class II		—	–811	—	–933	—	–1,055	ps
SSTL-2 class I		—	–485	—	–558	—	–631	ps
SSTL-2 class II		—	–758	—	–872	—	–986	ps
LVDS		—	–998	—	–1,148	—	–1,298	ps

**Table 4–43. Cyclone I/O Standard Output Delay Adders for Fast Slew Rate on Row Pins (Part 1 of 2)**

Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	—	0	—	0	—	0	ps
	4 mA	—	–489	—	–563	—	–636	ps
	8 mA	—	–855	—	–984	—	–1,112	ps
	12 mA	—	–993	—	–1,142	—	–1,291	ps
3.3-V LVTTTL	4 mA	—	0	—	0	—	0	ps
	8 mA	—	–347	—	–400	—	–452	ps
	12 mA	—	–858	—	–987	—	–1,116	ps
	16 mA	—	–819	—	–942	—	–1,065	ps
	24 mA	—	–993	—	–1,142	—	–1,291	ps
2.5-V LVTTTL	2 mA	—	329	—	378	—	427	ps
	8 mA	—	–661	—	–761	—	–860	ps
	12 mA	—	–655	—	–754	—	–852	ps
	16 mA	—	–795	—	–915	—	–1,034	ps

**Table 4–43. Cyclone I/O Standard Output Delay Adders for Fast Slew Rate on Row Pins (Part 2 of 2)**

Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
1.8-V LVTTTL	2 mA	—	1,290	—	1,483	—	1,677	ps
	8 mA	—	4	—	4	—	5	ps
	12 mA	—	–208	—	–240	—	–271	ps
1.5-V LVTTTL	2 mA	—	2,288	—	2,631	—	2,974	ps
	4 mA	—	608	—	699	—	790	ps
	8 mA	—	292	—	335	—	379	ps
3.3-V PCI (1)		—	–877	—	–1,009	—	–1,141	ps
SSTL-3 class I		—	–410	—	–472	—	–533	ps
SSTL-3 class II		—	–811	—	–933	—	–1,055	ps
SSTL-2 class I		—	–485	—	–558	—	–631	ps
SSTL-2 class II		—	–758	—	–872	—	–986	ps
LVDS		—	–998	—	–1,148	—	–1,298	ps

**Table 4–44. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Column Pins (Part 1 of 2)**

I/O Standard		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	—	1,800	—	2,070	—	2,340	ps
	4 mA	—	1,311	—	1,507	—	1,704	ps
	8 mA	—	945	—	1,086	—	1,228	ps
	12 mA	—	807	—	928	—	1,049	ps
3.3-V LVTTTL	4 mA	—	1,831	—	2,105	—	2,380	ps
	8 mA	—	1,484	—	1,705	—	1,928	ps
	12 mA	—	973	—	1,118	—	1,264	ps
	16 mA	—	1,012	—	1,163	—	1,315	ps
	24 mA	—	838	—	963	—	1,089	ps
2.5-V LVTTTL	2 mA	—	2,747	—	3,158	—	3,570	ps
	8 mA	—	1,757	—	2,019	—	2,283	ps
	12 mA	—	1,763	—	2,026	—	2,291	ps
	16 mA	—	1,623	—	1,865	—	2,109	ps
1.8-V LVTTTL	2 mA	—	5,506	—	6,331	—	7,157	ps
	8 mA	—	4,220	—	4,852	—	5,485	ps
	12 mA	—	4,008	—	4,608	—	5,209	ps

## Document Revision History

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February 2005 v1.1	Updated Figure 5-1.	—
May 2003 v1.0	Added document to Cyclone Device Handbook.	—